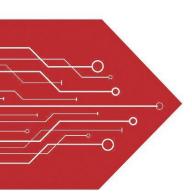
MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data speet

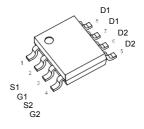


Product Summary

30V

 V_{DS}

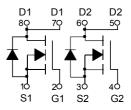
$$\begin{split} &I_D \ (at \ V_{GS} {=} 10 V) & 6A \\ &R_{DS(ON)} \ (at \ V_{GS} {=} 10 V) & < 30 m \Omega \\ &R_{DS(ON)} \ (at \ V_{GS} {=} 4.5 V) & < 42 m \Omega \end{split}$$



SOP-8

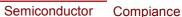
General Description

The AO4812-MSuses advanced trench technology to provide excellent RDS(ON) and low gate charge. This device is suitable for use as a load switch or in PWM applications.



N-Channel MOSFET

Parameter		Symbol	Maximum		Units	
Drain-Source Voltage		V_{DS}	30		V	
Gate-Source Voltage		V_{GS}	±20		V	
Continuous Drain T _A =25°C				6		
Current	T _A =70°C				5	
Pulsed Drain Current ^C		I _{DM}	30			
Avalanche Current ^C		I _{AS} , I _{AR}	10		А	
Avalanche energy L=0.1mH ^C		E _{AS} , E _{AR}	5		mJ	
	T _A =25°C		P _D		2	W
Power Dissipation ^B	T _A =70°C			1.3		VV
Junction and Storage Temperature Range		T_J , T_{STG}	-55 to 150		°C	
Thermal Characteris	stics					
Parameter		Symbol	Тур	Max	Units	
Maximum Junction-to-	Ambient ^A	t ≤ 10s	В	48	62.5	°C/W
Maximum Junction-to-Ambient A D Steady-State		Steady-State	$R_{\theta JA}$	74	90	°C/W
Maximum Junction-to-Lead Steady-State		$R_{\theta JL}$	32	40	°C/W	









Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =-250μA, V _{GS} =0V		30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V T _J =55°C				1	μА
						5	
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} I _D =250μA		1.2	1.8	2.4	V
I _{D(ON)}	On state drain current	V _{GS} =10V, V _{DS} =5V		30			Α
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =6A			25	30	0
			T _J =125°C		40	48	mΩ
		V _{GS} =4.5V, I _D =5A			33	42	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =6A			15		S
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V			0.76	1	V
Is Maximum Body-Diode Continuous Current					2.5	Α	
DYNAMIC	CPARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, f=1MHz V _{GS} =0V, V _{DS} =0V, f=1MHz			255	310	pF
C _{oss}	Output Capacitance				45		pF
C _{rss}	Reverse Transfer Capacitance				35	50	pF
R _g	Gate resistance			1.6	3.25	4.9	Ω
SWITCHI	NG PARAMETERS						
Q _{g(10V)}	Total Gate Charge	- - - - - - - - - - - - - - - - - - -			5.2	6.3	nC
Qg _(4.5V)					2.55	3.2	nC
Q_{gs}	Gate Source Charge				0.85		nC
Q_{gd}	Gate Drain Charge				1.3		nC
t _{D(on)}	Turn-On DelayTime	V_{GS} =10V, V_{DS} =15V, R_L =2.5 Ω , R_{GEN} =3 Ω			4.5		ns
t _r	Turn-On Rise Time				2.5		ns
t _{D(off)}	Turn-Off DelayTime				14.5		ns
t _f	Turn-Off Fall Time				3.5		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =6A, dI/dt=100A/μs			8.5		ns
Q _{rr}	Body Diode Reverse Recovery Charge	l _F =6A, dl/dt=100A/μs			2.2		nC

A. The value of R_{0JA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}$ =150°C, using $\leqslant~10s$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C. Ratings are based on low frequency and duty cycles to keep

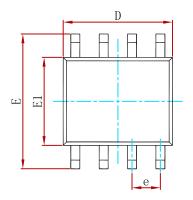
D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

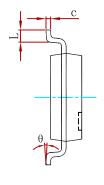
E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

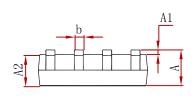
F. These curves are based on the junction-to-ambient thermal impedence which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(MAX)}$ =150°C. The SOA curve provides a single pulse ratin g.



PACKAGE MECHANICAL DATA

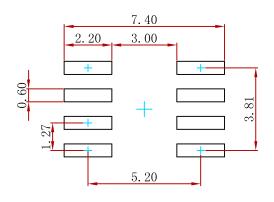






Symbol	Dimensions I	n Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1.350	1.750	0.053	0.069	
A1	0.100	0. 250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
c	0.170	0. 250	0.007	0.010	
D	4.800	5.000	0. 189	0. 197	
e	1.270 (BSC)		0.050 (BSC)		
Е	5.800	6. 200	0. 228	0. 244	
E1	3.800	4.000	0. 150	0. 157	
L	0.400	1. 270	0.016	0.050	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AO4812-MS	SOP-8	3000



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